



Reliability Data Report

Product Family R003

LT1021 LT1031 LT1236 LH0070

Reliability Data Report

Report Number: R003

Report generated on: Wed Sep 19 09:54:13 PDT 2012

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (125°C) ¹	No. of FAILURES ^{2,3}
HERMETIC	4266	8506	0628	9331	0
PLASTIC DIP	2651	8601	9906	7508	0
SOIC/SOT/MSOP	277	8501	9510	1341	0
TO-92	89	9118	9118	526	0
FLATPACK	240	0012	0205	556	0
Totals	7,523	-	-	19,262	0

HIGHLY ACCELERATED STRESS TEST AT +131 DEG C / 85% RH					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS (+85°C) ⁴	No. of FAILURES
PLASTIC DIP	95	9136	9443	156	0
SOIC/SOT/MSOP	384	9510	9548	477	0
Totals	479	-	-	633	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	No. of FAILURES
PLASTIC DIP	23413	9501	0317	850	0
SOIC/SOT/MSOP	17959	9503	1119	770	0
Totals	41,372	-	-	1,620	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
HERMETIC	933	8506	0631	103	0
PLASTIC DIP	2047	9136	0832	555	0
SOIC/SOT/MSOP	7906	8725	1119	1762	0
TO-92	45	9119	9119	11	0
FLATPACK	85	0012	0346	8	0
Totals	11,016	-	-	2,439	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
HERMETIC	411	8709	0631	15	0
PLASTIC DIP	1685	9136	0104	445	0
SOIC/SOT/MSOP	8778	8725	1119	1935	0
FLATPACK	68	0012	0346	1	0
Totals	10,942	-	-	2,396	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =0.1 FITS

(3) Mean Time Between Failure in Years = 1199465.88

(4) Assumes 20X Acceleration from 85 °C to +131 °C

Note 1: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL Preconditioning